Docket No.: 112764-200

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Kenneth M. Friedland, et al.

Serial No. 09/307,187

Filed: May 7, 1999

Group Art Unit: 2761

Examiner:

COMPUTER IMPLEMENTED RESOURCE ALLOCATION MODEL AND PROCESS TO DYNAMICALLY AND OPTIMALLY SCHEDULE AN ARBITRARY NUMBER OF RESOURCES SUBJECT TO AN ARBITRARY NUMBER OF CONSTRAINTS IN THE MANAGED CARE, HEALTH CARE AND/OR PHARMACY INDUSTRY

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents and Trademarks Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Respectfully submitted,

Registration No. 35,120

600 Fourteenth Street Washington, DC 20005

(202) 220-1200

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